

<b>Notice of References Cited</b>		Application/Control No. 10/554,059	Applicant(s)/Patent Under Reexamination OTOMO ET AL.	
		Examiner ROBERT S. WALTERS JR	Art Unit 1792	Page 1 of 1

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	U	Lee et al. "Single-Bond Formation and Characterization with a Scanning Tunneling Microscope" Science 286, 1719 (1999).
	V	Costela et al. "N-acetyl-4-nitro-1-naphthylamine as Sensitizer of N,N-dimethylaniline for Photoinitiated Radical Polymerization" Polymer Vol. 41, Issue 22, Oct. 2000.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.